

# ***N t i c   o f   R e f e r e n c e s   C i t e d***

Application/Control No.

09/333,049

Applicant(s)/Patent Under  
Reexamination  
HIRANO ET AL.

Examiner

Hoai V Pham

Art Unit

2814

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## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
	A	US-6174766B1	01-2001	Hayashi et al.	438	241
	B	US-				
	C	US-				
	D	US-				
	E	US-				
	F	US-				
	G	US-				
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	I	US-				
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	K	US-				
	L	US-				
	M	US-				

## **FOREIGN PATENT DOCUMENTS**

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## **NON-PATENT DOCUMENTS**

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